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- Output Ports Have Equivalent 25-Ω Series Resistors, So No External Resistors Are Required
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V<sub>OLP</sub> (Output Ground Bounce) < 1 V at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C
- Package Options Include Plastic Small-Outline (DW) Package, Ceramic Chip Carriers (FK), and Plastic (NT) and Ceramic (JT) DIPs

#### description

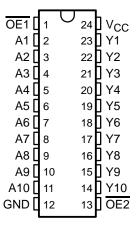
These 10-bit buffers or bus drivers provide a high-performance bus interface for wide data paths or buses carrying parity.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable (OE1 or OE2) input is high, all ten outputs are in the high-impedance state. The 'ABT2827 provide true data at their outputs.

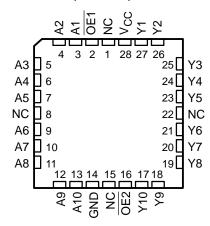
To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The outputs, which are designed to source or sink up to 12 mA, include equivalent 25- $\Omega$  series resistors to reduce overshoot and undershoot.

#### SN54ABT2827 . . . JT PACKAGE SN74ABT2827 . . . DW OR NT PACKAGE (TOP VIEW)



## SN54ABT2827 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

The SN54ABT2827 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT2827 is characterized for operation from –40°C to 85°C.



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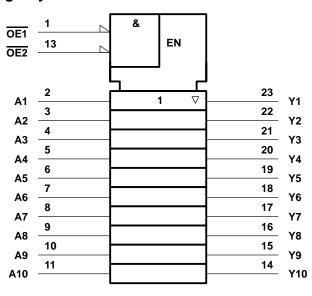
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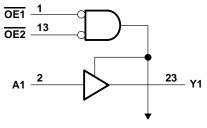
#### **FUNCTION TABLE**

	INPUTS	OUTPUT	
OE1	OE2	Α	Y
L	L	L	L
L	L	Н	Н
Н	X	Χ	Z
Х	Н	Χ	Z

## logic symbol†



### logic diagram (positive logic)



**To Nine Other Channels** 

Pin numbers shown are for the DW, JT, and NT packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V <sub>O</sub>	–0.5 V to 5.5 V
Current into any output in the low state, I <sub>O</sub> : SN54ABT2827	96 mA
SN74ABT2827	128 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–18 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DW package	81°C/W
NT package	67°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

<sup>2.</sup> The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.

## recommended operating conditions (see Note 3)

		SN54ABT2827		SN74ABT2827		UNIT
		MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	EN	2		V
VIL	Low-level input voltage		0.8		0.8	V
٧ <sub>I</sub>	Input voltage	0<	Vcc	0	VCC	V
loh	High-level output current	<b>/</b> 2,	-12		-12	mA
loL	Low-level output current	700	12		12	mA
Δt/Δν	Input transition rise or fall rate	J. Y.	5		5	ns/V
TA	Operating free-air temperature	<b>–</b> 55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T <sub>A</sub> = 25°C			SN54ABT2827		SN74ABT2827		UNIT
PARAMETER			MIN	TYP <sup>†</sup>	MAX	MIN	MAX	MIN	MAX	UNII
VIK	V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2		-1.2		-1.2	V
	V <sub>CC</sub> = 4.5 V,	I <sub>OH</sub> = -1 mA	2.5			2.5		2.5		
Vali	V <sub>CC</sub> = 5 V,	I <sub>OH</sub> = -1 mA	3			3		3		V
VOH	V <sub>CC</sub> = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.4			2.4		2.4		
	VCC = 4.5 V	$I_{OH} = -12 \text{ mA}$	2			2		2		
VOL	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 12 mA			0.8		0.8		0.8	V
V <sub>hys</sub>				100						mV
lį	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	$V_I = V_{CC}$ or GND			±1		#		±1	μΑ
lozh	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 2.7 V			10‡		10		10‡	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.5 V$			<b>-10</b> ‡		<b>–</b> 10		-10‡	μΑ
l <sub>off</sub>	$V_{CC} = 0$ ,	$V_I$ or $V_O \le 4.5 \text{ V}$			±100	\ \ \	· 6		±100	μΑ
ICEX	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 5.5 V	Outputs high			50	3	50		50	μΑ
ΙΟ <sup>§</sup>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.5 V	-50	-140	-225‡	-50	-225‡	-50	-225‡	mA
	V <sub>CC</sub> = 5.5 V,	Outputs high		80	250	Q	250		250	μΑ
l <sub>CC</sub>	IO = 0, VI = VCC or GND	Outputs low		35	40‡		40‡		40‡	mA
		Outputs disabled		80	250		250		250	μΑ
	V <sub>CC</sub> = 5.5 V, One input at 3.4 V, Other inputs at	Outputs enabled			1.5		1.5		1.5	mA
Δlcc¶		Outputs disabled			50		50		50	μΑ
	V <sub>CC</sub> or GND	Control inputs			1.5		1.5		1.5	mA
C <sub>i</sub>	V <sub>I</sub> = 2.5 V or 0.5 V			4						pF
Co	V <sub>O</sub> = 2.5 V or 0.5 V			8.5						pF

 $<sup>\</sup>overline{\dagger}$  All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.



<sup>&</sup>lt;sup>‡</sup>This data sheet limit may vary among suppliers.

<sup>§</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

<sup>¶</sup> This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

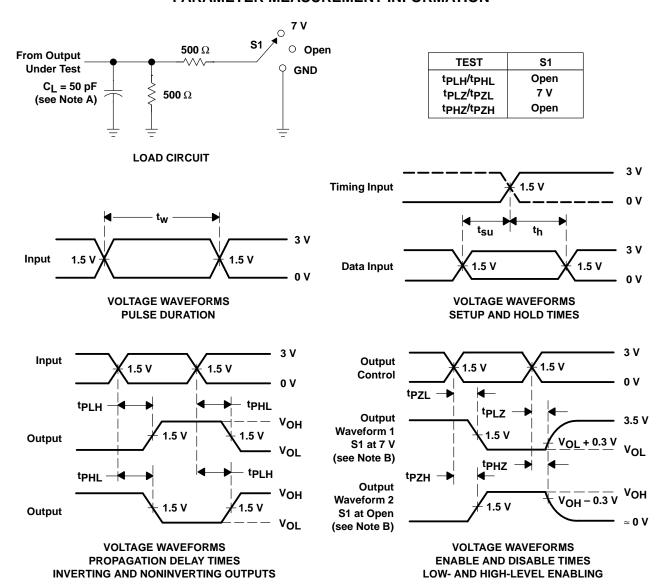
## SN54ABT2827, SN74ABT2827 10-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C			SN54ABT2827		SN74ABT2827		UNIT
	(IIII O1)	(0011 01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	۸	V	1.1	3.3	5.1	1.1	5.6	1.1	5.5	no
<sup>t</sup> PHL	A	Ť	1.1	2.7	4.5	1.1	5.2	1.1	5.1	ns
<sup>t</sup> PZH	ŌĒ	Y	1	4	5.9	1	6.8	1	6.7	
<sup>t</sup> PZL			1	4.2	6.8	37	8	1	7.8	ns
<sup>t</sup> PHZ	ŌĒ	V	2	5.3	6.7	0 2	7.4	2	7.2	
<sup>t</sup> PLZ	OE	Ť	1.3	4.8	7.2	1.3	8.5	1.3	7.5	ns

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_\Gamma \leq$  2.5 ns,  $t_f \leq$  2.5 n
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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